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| <b>Notice of References Cited</b> | Application/Control No.<br>10/673,501 | Applicant(s)/Patent Under<br>Reexamination<br>MITROVIC, ANDREJ S. |             |
|                                   | Examiner<br>Akash Saxena              | Art Unit<br>2128  | Page 1 of 2 |

#### U.S. PATENT DOCUMENTS

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name                    | Classification |
|---|---|--|-----------------|-------------------------|----------------|
|   | A | US-6,802,045                                     | 10-2004         | Sonderman et al.        | 703/22         |
|   | B | US-6,615,097                                     | 09-2003         | Ozaki, Hiroji           | 703/22         |
|   | C | US-5,719,796                                     | 02-1998         | Chen, Vincent Ming Chun | 703/13         |
|   | D | US-6,905,895                                     | 06-2005         | Coss et al.             | 438/16         |
|   | E | US-6,812,045                                     | 11-2004         | Nikoonahad et al.       | 438/14         |
|   | F | US-6,774,998                                     | 08-2004         | Wright et al.           | 356/401        |
|   | G | US-6,763,277                                     | 07-2004         | Allen et al.            | 700/100        |
|   | H | US-6,757,645                                     | 06-2004         | Chang et al.            | 703/13         |
|   | I | US-6,728,591                                     | 04-2004         | Hussey et al.           | 700/121        |
|   | J | US-6,643,616                                     | 11-2003         | Granik et al.           | 703/13         |
|   | K | US-6,628,809                                     | 09-2003         | Rowe et al.             | 382/115        |
|   | L | US-6,618,856                                     | 09-2003         | Coburn et al.           | 717/135        |
|   | M | US-6,571,371                                     | 05-2003         | Coss et al.             | 716/4          |

#### FOREIGN PATENT DOCUMENTS

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
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|   | P |  |                 |         |      |                |
|   | Q |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

#### NON-PATENT DOCUMENTS

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)  |
|---|---|--|
|   | U | "Emerging Paradigms in Semiconductor Manufacturing"; Paul P. Castrucci; 1990 Int'l Semiconductor Mfg. Science Symposium; IEEE 1990   |
|   | V | "Mathematic-Physical Engine: Parallel Processing for Modeling and Simulation of Physical Phenomena"; V.K.Jain et al; IEEE 1994   |
|   | W | "Conceptual Framework for Manufacturing Service Provisioning by Virtual Fabs"; Yea-Huey Su et al; 1998 NSC Republic Of China; 1998 Semiconductor Mfg. Technology Workshop.                   |
|   | X | "New approaches for Simulation of Wafer Fabrication: The Use of Control Variates and Calibration Metrics" Chanettre Rasmidatta et al; Proceedings of 2002 Winter Simulation Conference; 2002 |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

|                                   |                                       |   |             |
|-----------------------------------|---------------------------------------|---|-------------|
| <b>Notice of References Cited</b> | Application/Control No.<br>10/673,501 | Applicant(s)/Patent Under<br>Reexamination<br>MITROVIC, ANDREJ S. |             |
|                                   | Examiner<br>Akash Saxena              | Art Unit<br>2128  | Page 2 of 2 |

**U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name              | Classification |
|---|---|--|-----------------|-------------------|----------------|
|   | A | US-5,866,437                                     | 02-1999         | Chen et al.       | 438/14         |
|   | B | US-2003/0078738                                  | 04-2003         | Wouters et al.    | 702/22         |
|   | C | US-2004/0044513                                  | 03-2004         | Kitahara, Noriaki | 703/017        |
|   | D | US-2004/0078319                                  | 04-2004         | Madhavan et al.   | 705/038        |
|   | E | US-2004/0102934                                  | 05-2004         | Chang, Fang-Cheng | 703/001        |
|   | F | US-2005/0016947                                  | 01-2005         | Fatke et al.      | 216/002        |
|   | G | US-2005/0010319                                  | 01-2005         | Patel et al.      | 700/121        |
|   | H | US-2004/0078319                                  | 04-2004         | Madhavan et al.   | 705/038        |
|   | I | US-2003/0135302                                  | 07-2003         | Hung et al.       | 700/245        |
|   | J | US-  |                 |                   |                |
|   | K | US-  |                 |                   |                |
|   | L | US-  |                 |                   |                |
|   | M | US-  |                 |                   |                |

**FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
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|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

**NON-PATENT DOCUMENTS**

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)  |
|---|---|--|
|   | U | "Detailed Simulation for Semiconductor Manufacturing"; Robert W. Atherton et al; Proceedings of the 1990 Winter Simulation Conference  |
|   | V | "Integrated CAM and Process Simulation to Enhance On-Line Analysis and Control of IC Fabrication"; Angus J. MacDonald et a; IEE Transctions on Semicinductor Mfg. Vol.3 No.2 May 1990. |
|   | W |  |
|   | X |  |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.